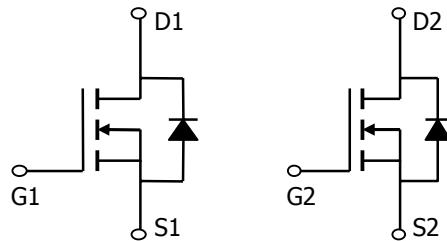
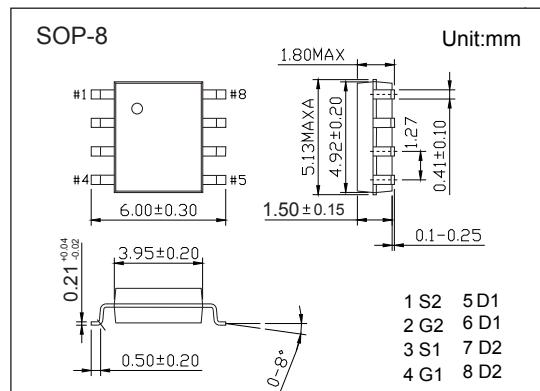


Dual N-Channel MOSFET

AO4850 (KO4850)

■ Features

- V_{DS} (V) = 75V
- I_D = 3.1A (V_{GS} = 10V)
- $R_{DS(ON)} < 130\text{m}\Omega$ (V_{GS} = 10V)
- $R_{DS(ON)} < 165\text{m}\Omega$ (V_{GS} = 4.5V)



■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	10 Sec	Steady State	Unit
Drain-Source Voltage	V_{DS}	± 25	75	V
Gate-Source Voltage	V_{GS}			
Continuous Drain Current	I_D	3.1	2.3	A
		2.4	1.8	
Pulsed Drain Current	I_{DM}	15		
Avalanche Current	I_{AR}	10		
Repetitive Avalanche Energy	E_{AR}	15		mJ
Power Dissipation	P_D	2	1.1	W
		1.3	0.7	
Thermal Resistance.Junction- to-Ambient	R_{thJA}	62.5	110	$^\circ\text{C}/\text{W}$
Thermal Resistance.Junction- to-Lead	R_{thJL}	50		
Junction Temperature	T_J	150		$^\circ\text{C}$
Storage Temperature Range	T_{stg}	-55 to 150		

Dual N-Channel MOSFET

AO4850 (KO4850)

■ Electrical Characteristics $T_a = 25^\circ\text{C}$

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V_{DSS}	$I_D=10\text{mA}, V_{GS}=0\text{V}$	75			V
Zero Gate Voltage Drain Current	$I_{DS(0)}$	$V_{DS}=75\text{V}, V_{GS}=0\text{V}$			1	μA
		$V_{DS}=75\text{V}, V_{GS}=0\text{V}, T_J=55^\circ\text{C}$			5	
Gate-Body Leakage Current	I_{GSS}	$V_{DS}=0\text{V}, V_{GS}=\pm 25\text{V}$			± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1		3	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=10\text{V}, I_D=3.1\text{A}$			130	$\text{m}\Omega$
		$V_{GS}=10\text{V}, I_D=3.1\text{A}, T_J=125^\circ\text{C}$			195	
		$V_{GS}=4.5\text{V}, I_D=2\text{A}$			165	
On State Drain Current	$I_{D(on)}$	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	15			A
Forward Transconductance	g_{FS}	$V_{DS}=5\text{V}, I_D=3.1\text{A}$			10	S
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}, V_{DS}=30\text{V}, f=1\text{MHz}$			290	pF
Output Capacitance	C_{oss}				54	
Reverse Transfer Capacitance	C_{rss}				24	
Gate Resistance	R_g	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$			2.4	3.5
Total Gate Charge (10V)	Q_g	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, I_D=3.1\text{A}$			5.14	nC
Total Gate Charge (4.5V)					2.34	
Gate Source Charge	Q_{gs}	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, I_D=3.1\text{A}$			0.97	nC
Gate Drain Charge	Q_{gd}				1.18	
Turn-On Delay Time	$t_{d(on)}$				4	ns
Turn-On Rise Time	t_r				3.4	
Turn-Off Delay Time	$t_{d(off)}$	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, R_L=9.7\Omega, R_{GEN}=3\Omega$			14.4	ns
Turn-Off Fall Time	t_f				2.4	
Body Diode Reverse Recovery Time	t_{rr}				30.2	nC
Body Diode Reverse Recovery Charge	Q_{rr}		$I_F = 3.1\text{A}, dI/dt = 100\text{A}/\mu\text{s}$		21.5	
Maximum Body-Diode Continuous Current	I_S					2.5 A
Diode Forward Voltage	V_{SD}	$I_S=1\text{A}, V_{GS}=0\text{V}$			1	V

Note. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

■ Marking

Marking	4850 KA****
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Dual N-Channel MOSFET

AO4850 (KO4850)

■ Typical Characteristics

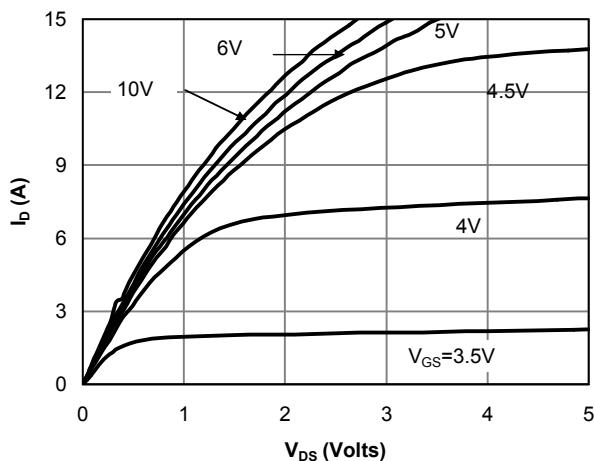


Fig 1: On-Region Characteristics

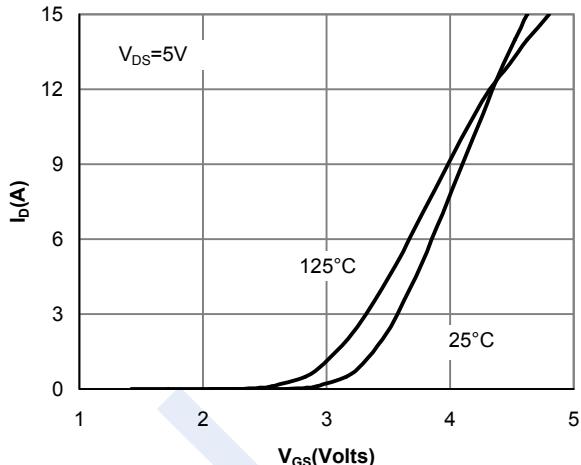


Figure 2: Transfer Characteristics

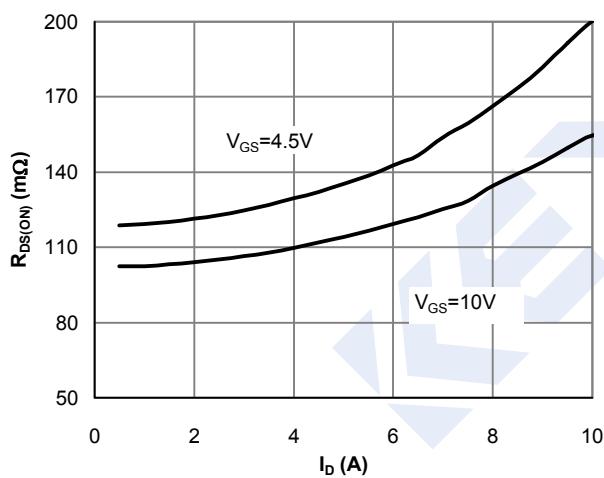


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

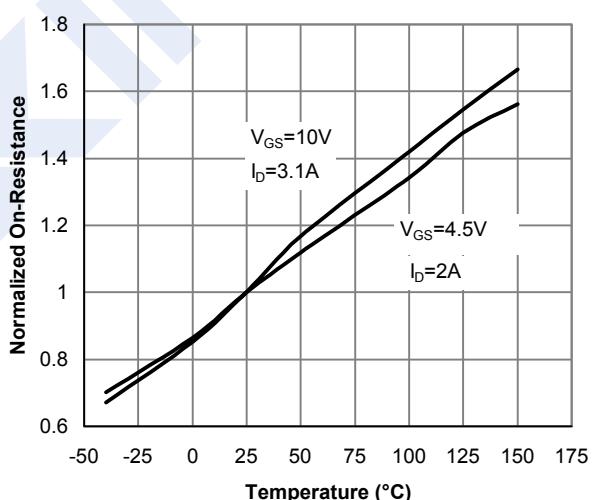


Figure 4: On-Resistance vs. Junction Temperature

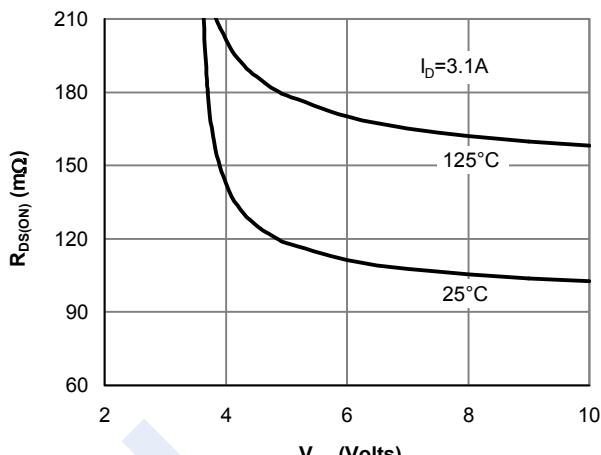


Figure 5: On-Resistance vs. Gate-Source Voltage

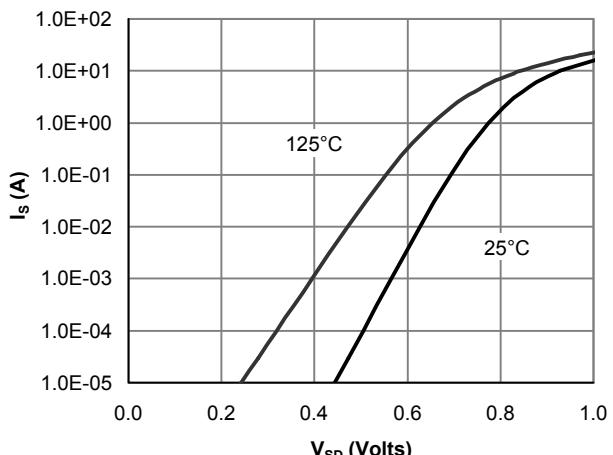


Figure 6: Body-Diode Characteristics

Dual N-Channel MOSFET

AO4850 (KO4850)

■ Typical Characteristics

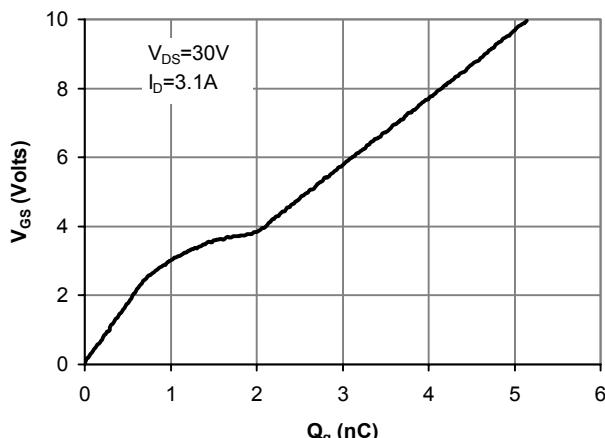


Figure 7: Gate-Charge Characteristics

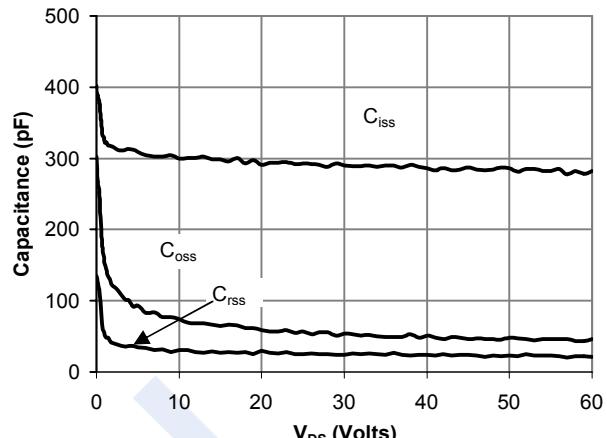


Figure 8: Capacitance Characteristics

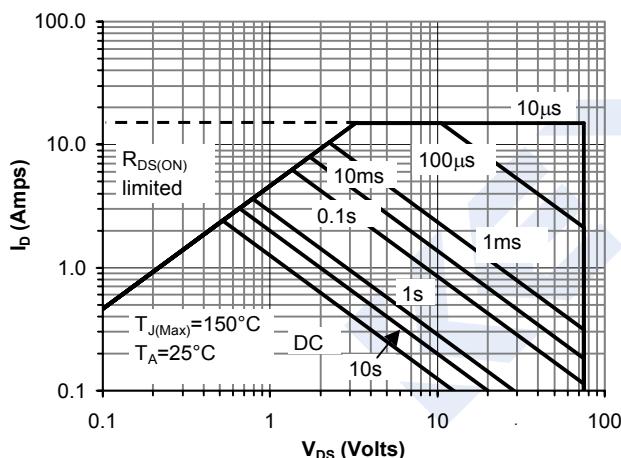


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

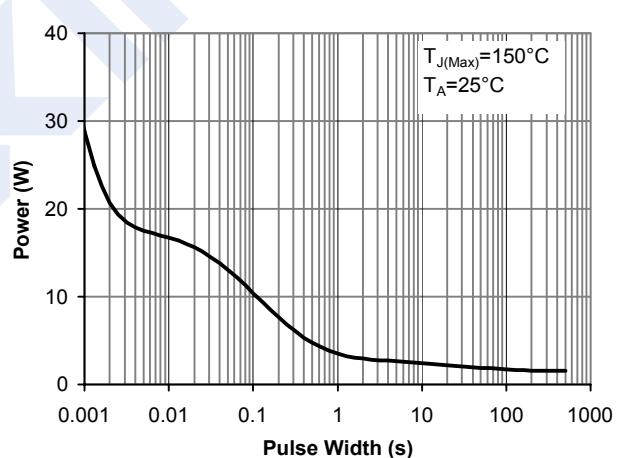


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

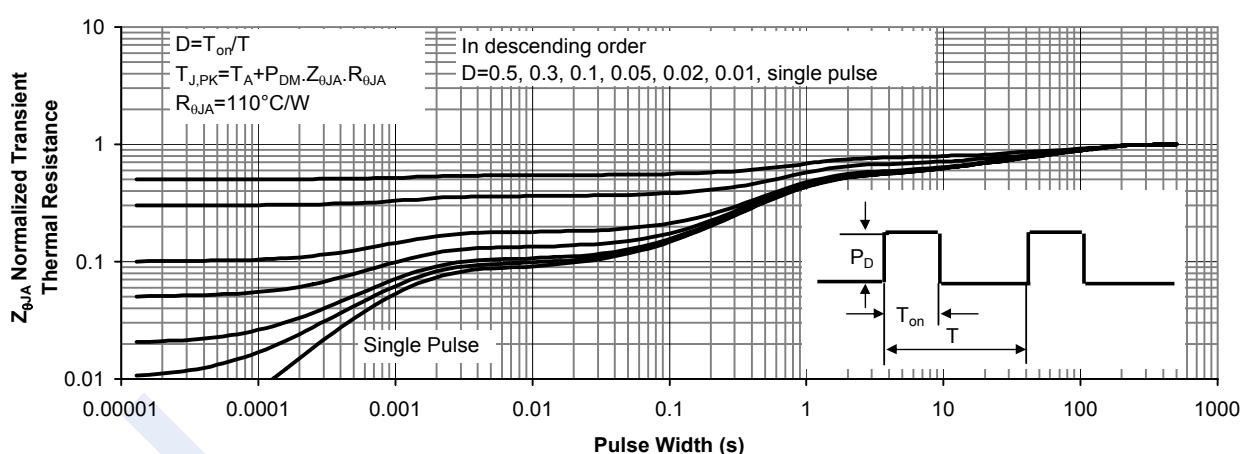


Figure 11: Normalized Maximum Transient Thermal Impedance